The M6 JETSTREAM: State of the Art



Bruker Nano Analytics, Berlin, Germany Webinar, November 9, 2017



Innovation with Integrity

M6 JETSTREAM Webinar Outline



Introduction

Presenters The M6 Jetstream Micro-XRF in art and conservation

Producing the data

Measurement parameters and options

• Evaluating the data "DATA MINING"

ROI fast deconvolution convolution or forward calculation ROI mathematics image processing

- Live part
- Summary

M6 JETSTREAM Webinar Presenters / Moderators





Falk Reinhardt

Application Scientist, Bruker Nano Analytics, Berlin, Germany



Dr. Roald Tagle Sr. Application Scientist, Bruker Nano Analytics, Berlin, Germany M6 Jetstream micro-XRF spectrometer Standard configuration

Instrument parameters

30 W micro-focus Rh tube with polycapillary lens for excitation spot sizes from 100 to 500 μ m (for Mo-Ka)

30 mm² silicon drift detector (SDD)

with energy resolution < 145 eV (for Mn-Ka) Option: 60 mm² detector

Sample stage with measureable area in one run

up to of **800 mm x 600 mm**

Sample stage speed up to 100 mm/s, and 200 mm/s²

Optional Helium flush with flow controller

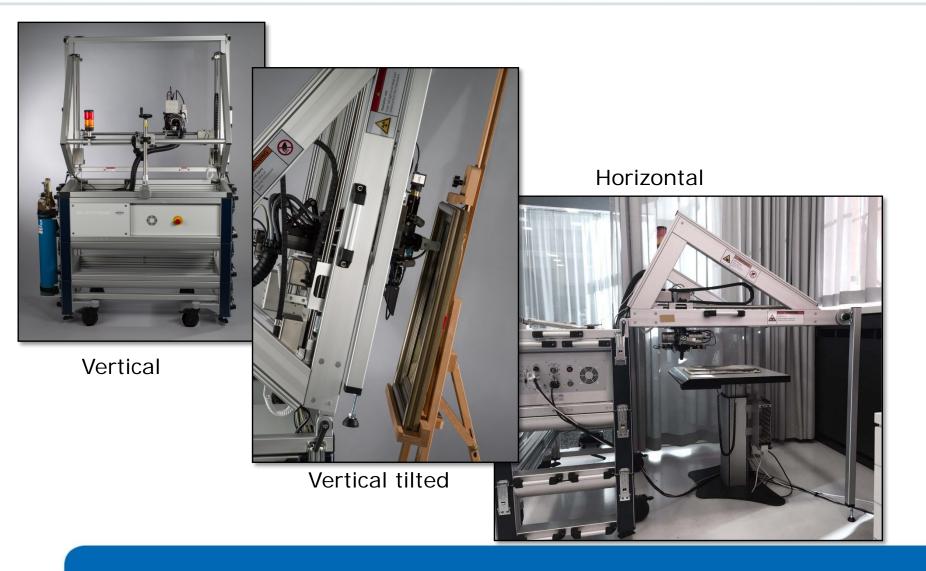






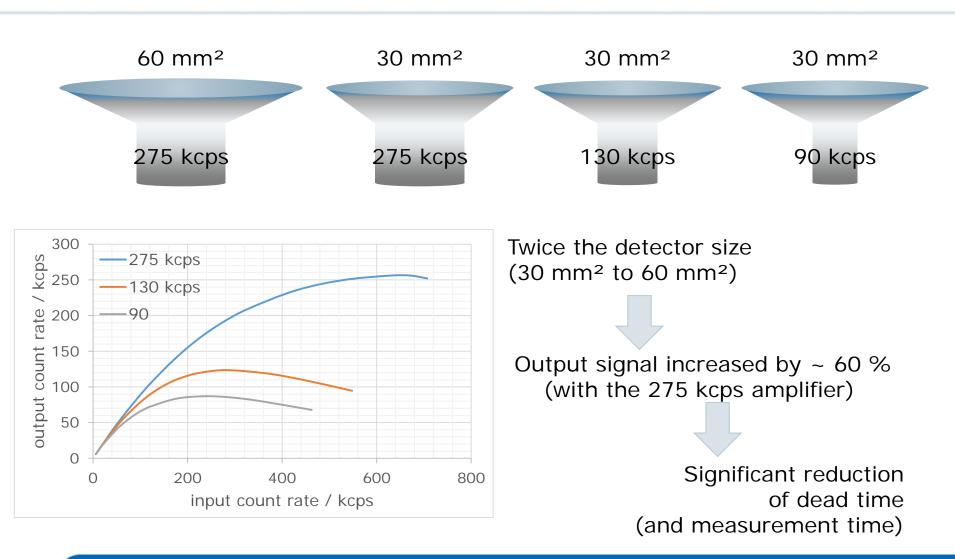
M6 Jetstream micro-XRF spectrometer Instrument operation





Improving the signal Larger detectors and fast signal processing

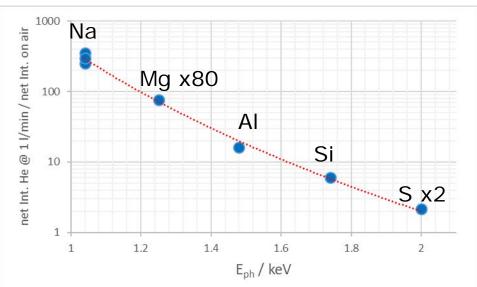




Improving the signal He flush for light element detection

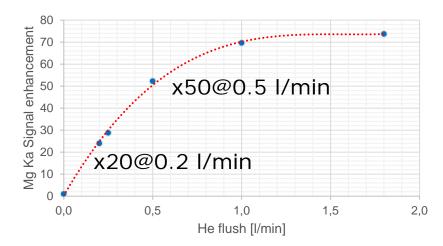


He flush adjustable, with integrated flow controller to operate between 0.2 I/min and 1.8 I/min

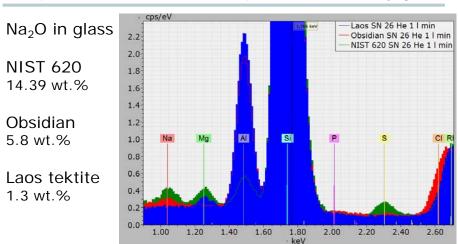


Values determined for a specific instrument, using pure element samples.

50 kV, 600 μA, working distance set for 100 μm spot, 30 mm² SDD, He flow rate: 1 l/min, in horizontal measurement orientation, Na-enhancement extrapolated

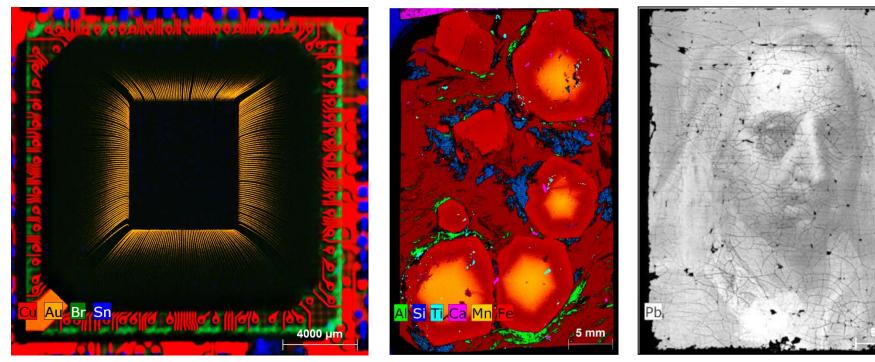


He consumption between 0.2 I/min and 0.5 I/min is a compromise between consumption and intensity gain



Micro-XRF features and benefits At a glance



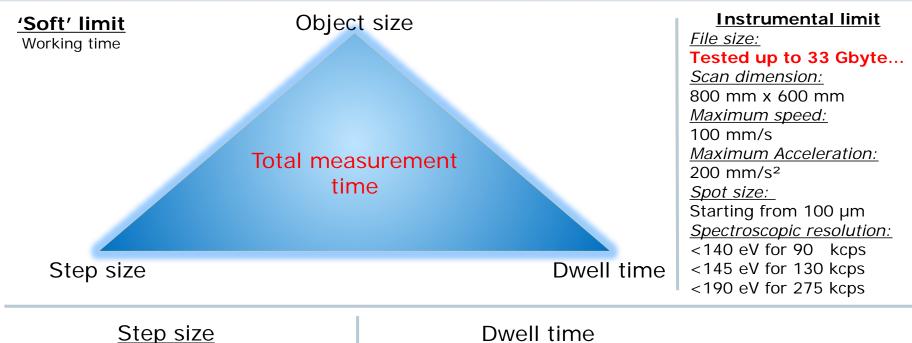


Information from the depth of the sample

Trace element sensitivity

No sample preparation





Should correspond to the size of the object that wants to be resolved

Painting \rightarrow 300 to 800 µm Drawings \rightarrow 100 to 300 µm

Note: small step size allows to improve statistic by use of binning

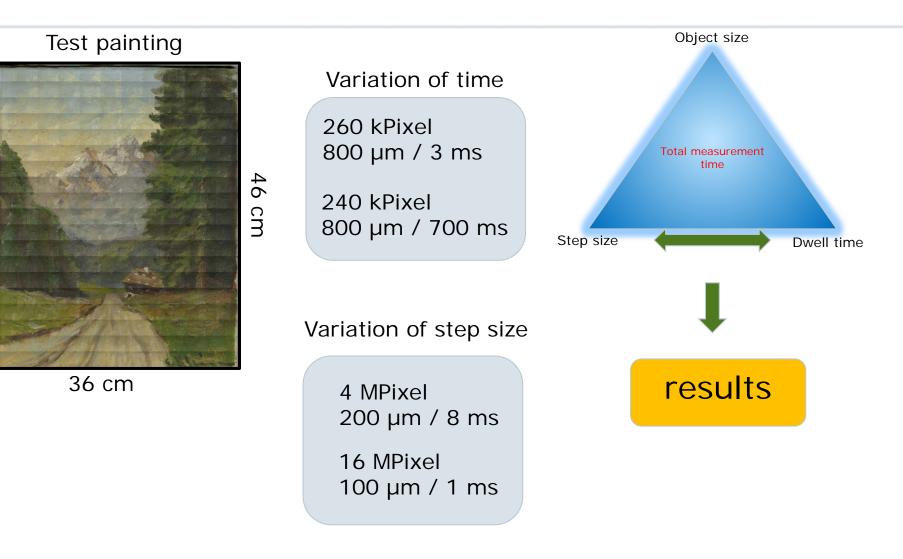
Dwell time

Short (< 10 ms) \rightarrow main elements and or elements for which the instrument is sensitive

> Dwell time reduction

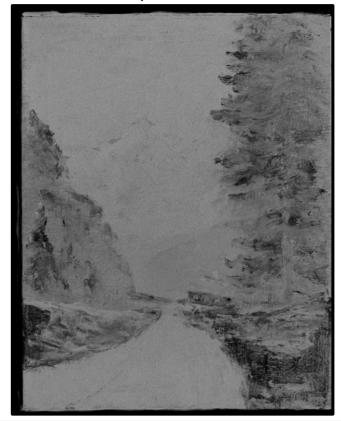
Improving the signal - larger detector \rightarrow 60 mm² - He flush



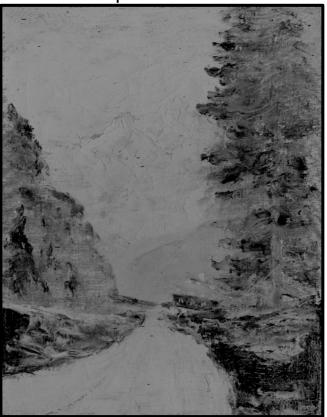




800 µm / 8 ms

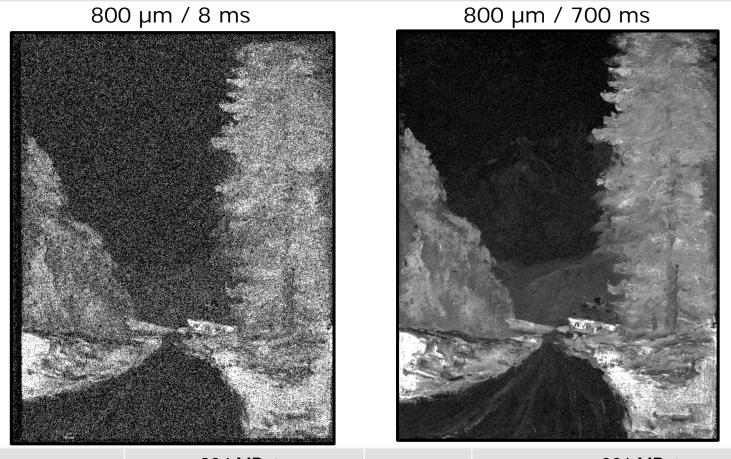


800 µm / 700 ms



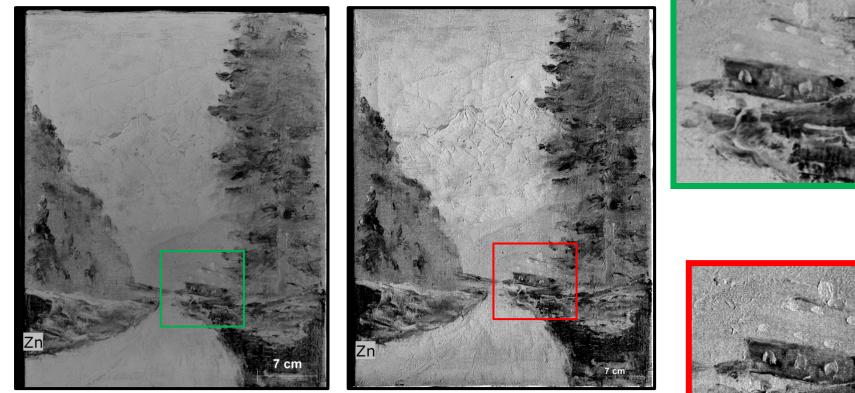
File	294 MByte	661 MByte
# of Spectra	260 kPixel	240 kPixel
Total time	1 h 35 min	48 h 32 min





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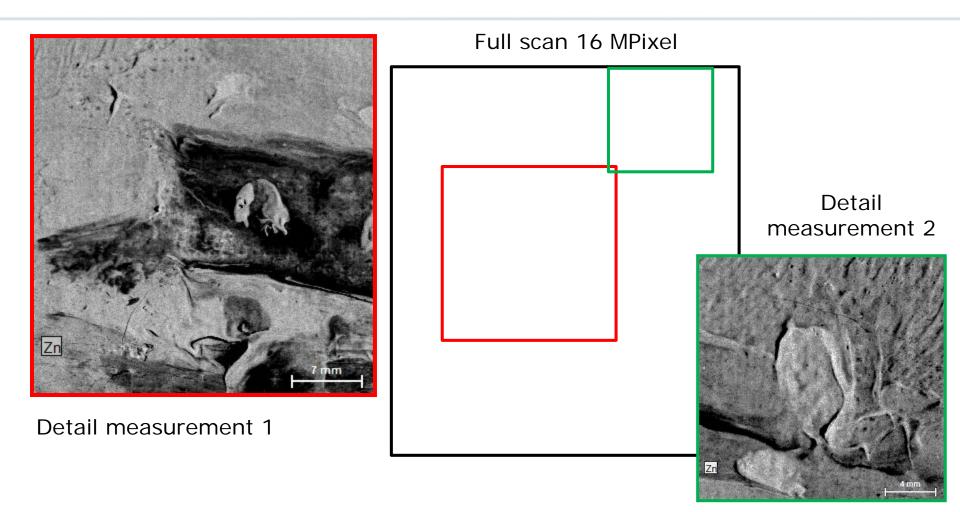


4 million

16 million



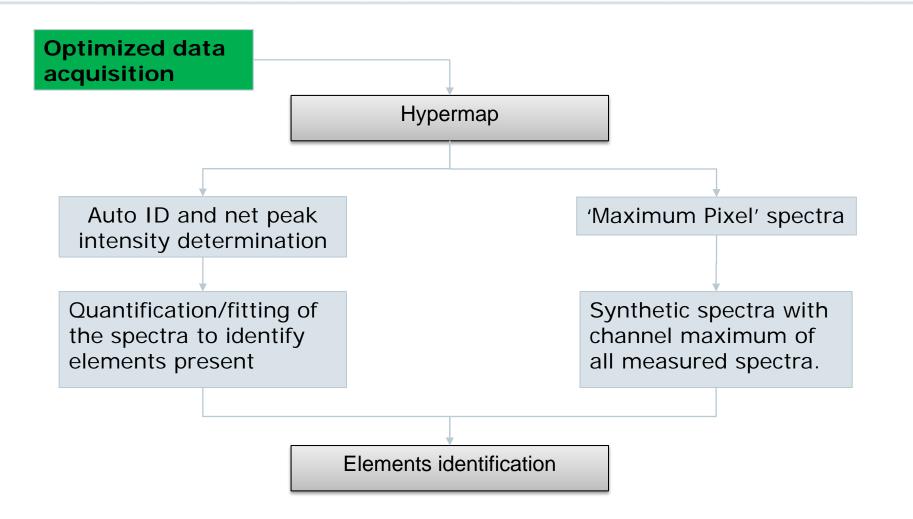






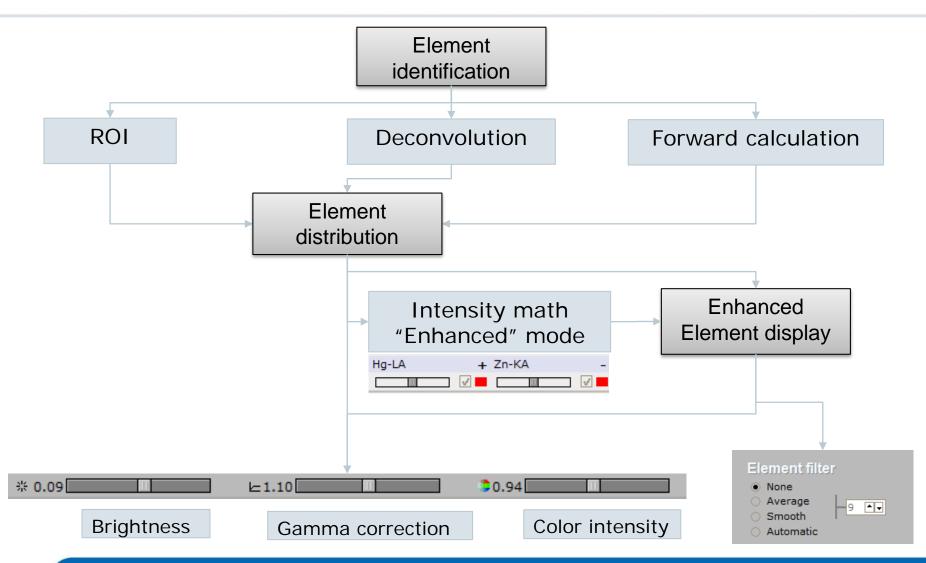
Now the data is there and the work starts: Data mining. What can be done?





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The Data:



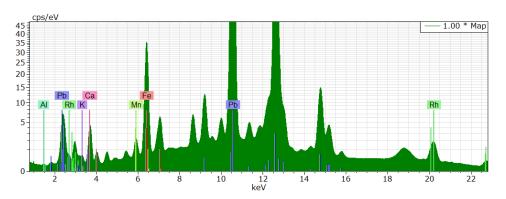


Mapping parameters		
Width:	916	pixel
	457.884	mm
Height:	640	pixel
	319.988	mm
Pixel Size:	500	μm
Total number of pixel:	586240	pixel
Acquisition parameters		
Frame count:	1	
Pixel time:	10	ms/pixel
Measure time:	1:14 h	
Overall time:	2:43 h	
Stage speed:	50.0	mm/s
Stage position (X,Y,Z):		
Tube parameter		
High voltage:	50	kV
Anode current:	600	μA
Filter:	Empty	
Optic:	Lens	
SpotSize:	25	
Chamber at:	Air 1055	mbar
Anode:	Rh	
Detector parameters		
Selected detectors:	1	
Max. pulse throughput:	275000	cps

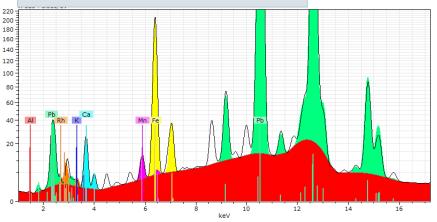
Data mining, Element identification: Auto ID and Interactive quantification



- The Auto ID does not identify all the elements. It is based on a quantification of all "allowed" elements.
- 2) False identifications are possible!

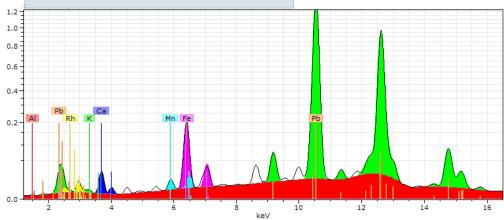


Fundamental parameter forward calculation



Bayes deconvolution

Quantify → XRF-Deconv rt

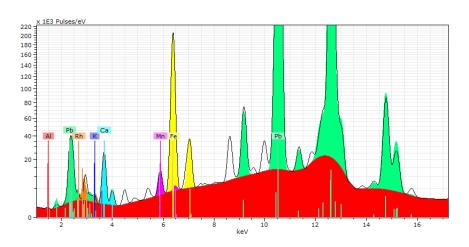


Data mining, Element identification: Interactive quantification using FP model



The M6's quantification iteratively varies the assumed sample composition and forward calculates the resulting spectra by repeatedly solving the Sherman Equation.

The prerequisite for a quantification is a homogenous, infinitely thick sample. ...which is rarely the case for a painting. Fundamental parameter forward calculation

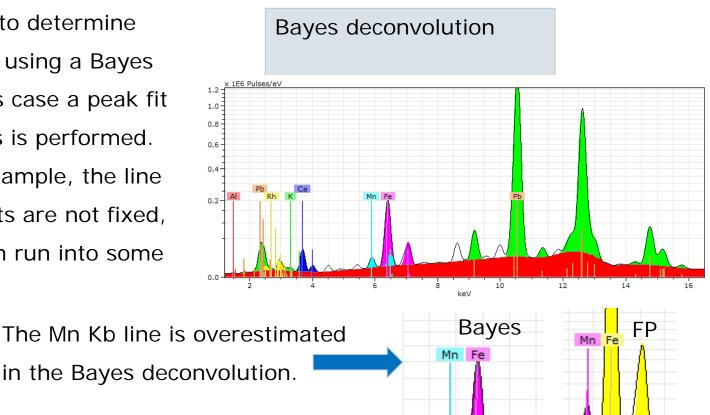


There is no forward calculated homogeneous, infinitely thick sample which produces a spectrum like the measured one. Therefore the fit cannot be perfect. However, for most of the samples the fit is surprisingly good. But problems might appear especially in the low energy range!

Data mining, Element identification: Interactive deconvolution using Bayes



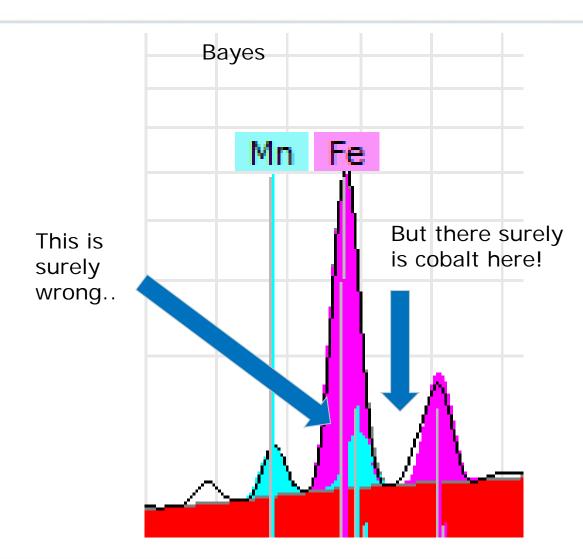
There is a possibility to determine the peak intensity by using a Bayes deconvolution. In this case a peak fit using Gaussian peaks is performed. However, since for example, the line ratios for the elements are not fixed, the deconvolution can run into some problems.



There is no correct solution, there are different tools, which have their pros and cons...

Data mining, Element identification: Interactive deconvolution using Bayes

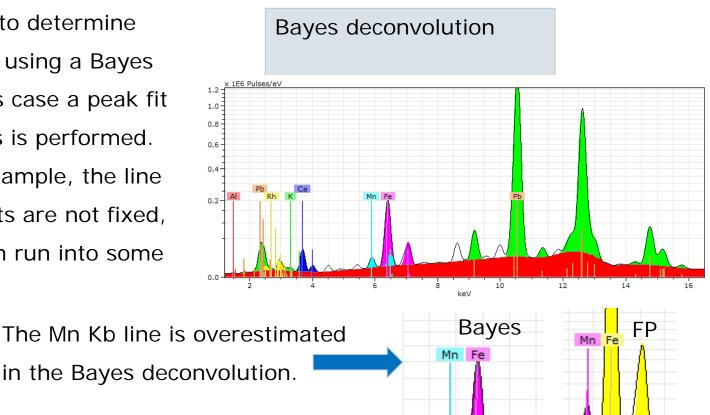




Data mining, Element identification: Interactive deconvolution using Bayes



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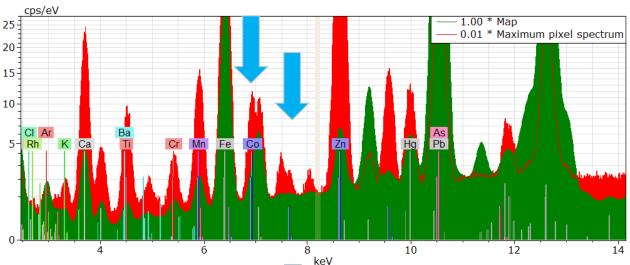


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Data mining, Element identification: Maximum Pixel spectra



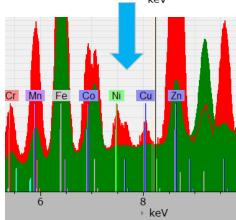




In the map spectrum the signal for Ni and Cu is "diluted" by the large number of spectra.

The Maximum pixel spectrum reflects the highest intensity per channel found in any pixel of the map.

Maximum pixel spectrum can be used to find hot spots in the data block.

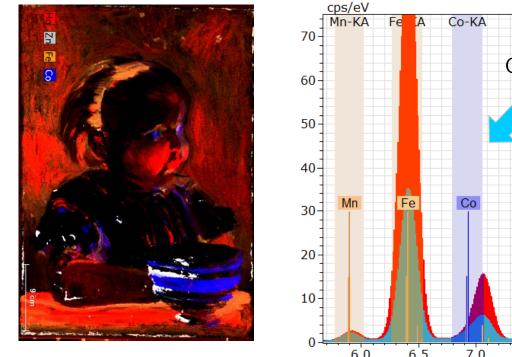


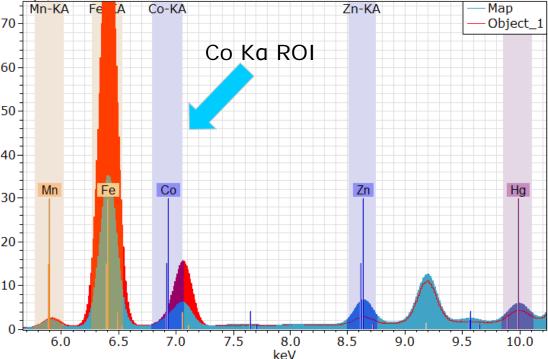
Easy identification of Ni and Cu presence somewhere in the sample.

An even the cobalt is no longer in question!

Data mining, Element display: Region of interest ROI







The ROI element display does not correct for peak overlapping or background. Thus, f.e. the Co intensity contains also parts of the K β from Fe.

Extremely fast and robust!

Data mining, Element display: Region of interest ROI



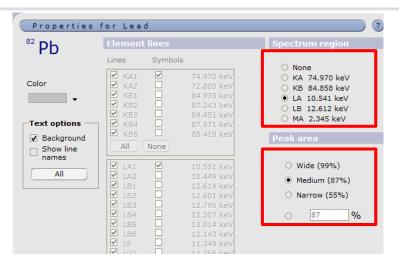
In the periodic table (right mouse on the element) it is possible to edit the lines that shall be used for the element display.

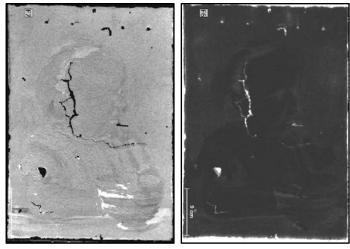
The Line as well as the width of the Region around the peak can be edited.

Note: only one line of an element can be displayed at a time. To display two lines of an element (Pb-M and -L) at the same time, a Free region can be used.



Free region can be use to display the intensity of any ROI in the spectrum, f.e. scattering background or total intensity.



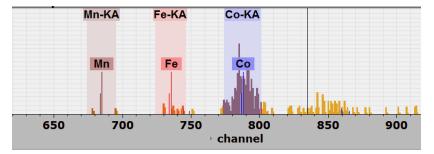


Total intensity

Compton

Data mining, Element display: Fast deconvolution

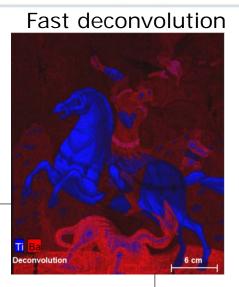


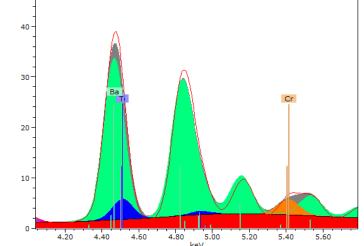


In the fast deconvolution (which is a fit) every count in every channel is weighted by the probability that a it belongs to one of the selected elements. As soon as this is calculated for each channel the complete data set is evaluated at high speed.

In this case 17 elements and half a million spectra were 'deconvoluted' in 30 seconds.





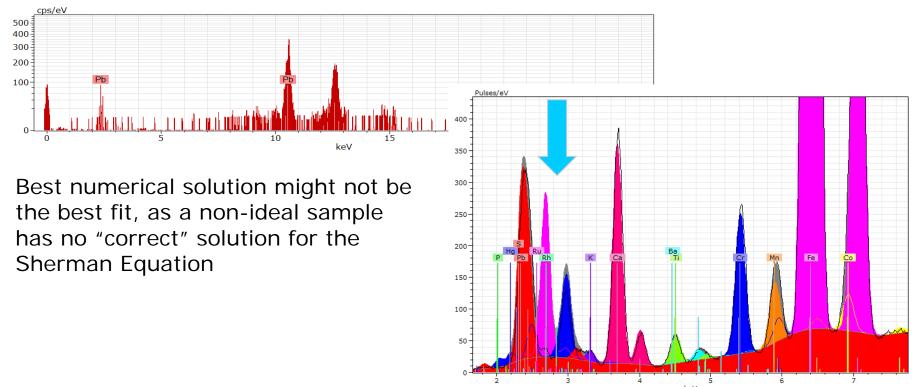


Data mining, Element display: Forward calculation I



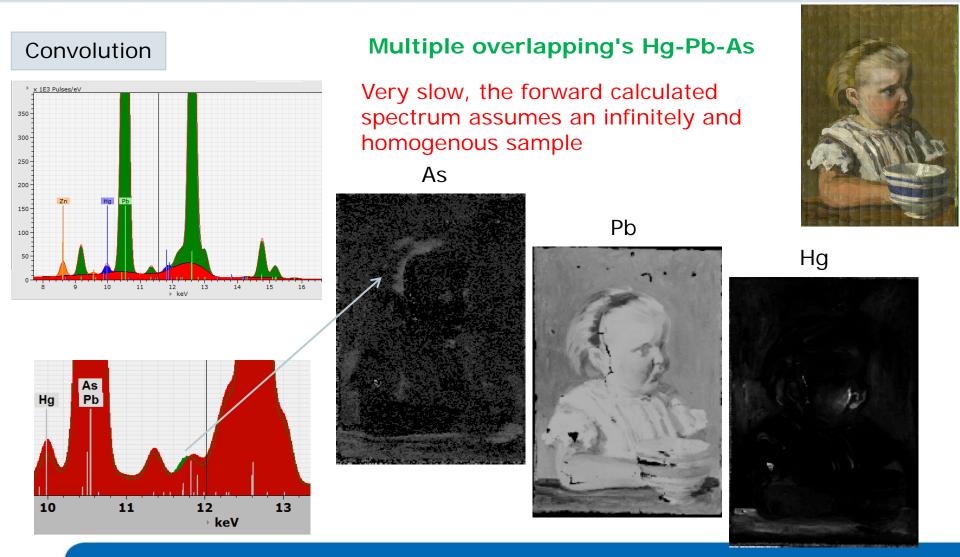
The quantification of a non-ideal sample is the main problem of this approach.

One spectrum acquired in short time might contain only a limited number of counts, e.g. 1500 counts in 4096 channels. Making an iterative spectrum fit and quantification unstable.



Data mining, Element display: Forward calculation





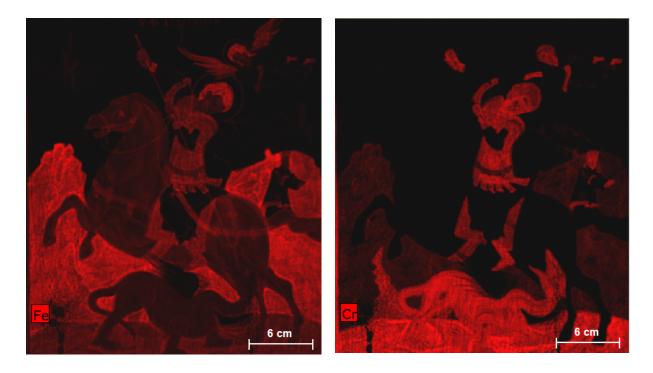
Data mining, Element display: Enhanced mode



Peak mathematics

Very fast, easy to implement, plenty of options

A bit complex to understand at the beginning. Requires experience (or talent)



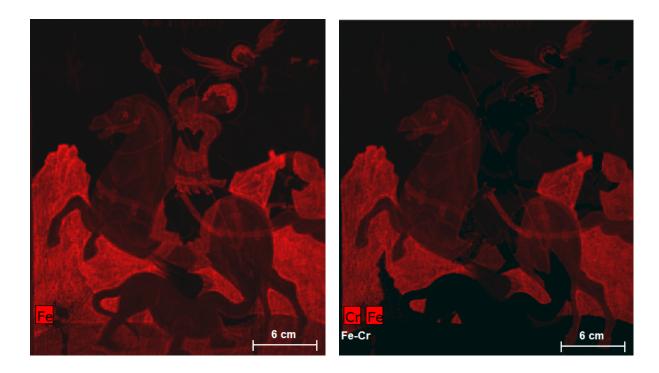
Data mining, Element display: Enhanced mode



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Data mining, visualization: Image parameters





By changing the slider position it is possible to highlight or oppress specific features

Data mining, visualization: Image parameters

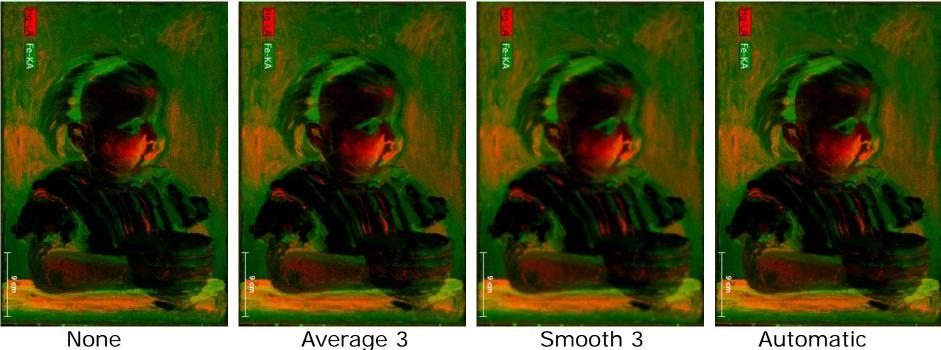




Gamma correction Brightness Color intensity

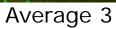
Data mining, visualization: Element filter

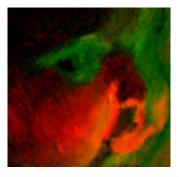


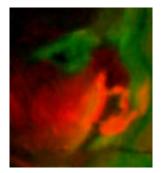


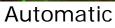
None





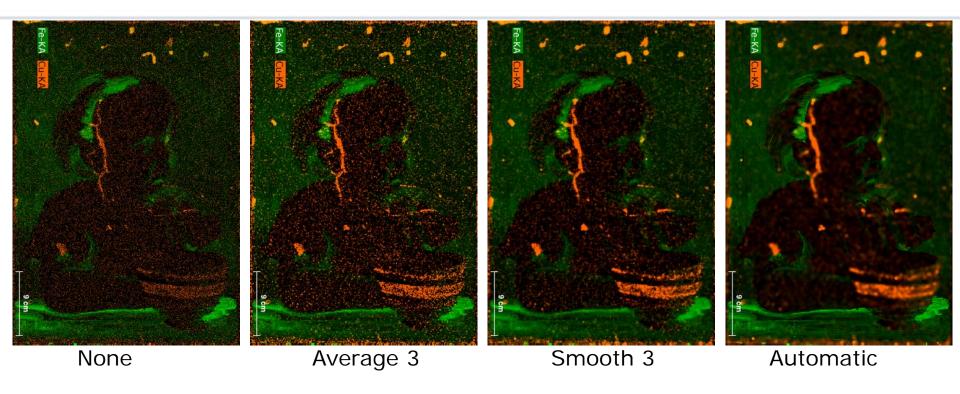






Data mining, visualization: Image parameters



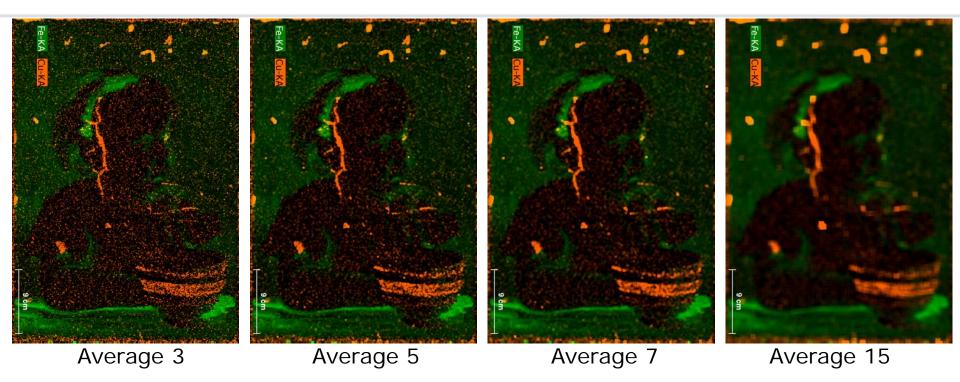


Automatic: every element displayed gets, after a statistical evaluation of the number of count in the data, an "optimal" binning or average number for the display.

... without telling, what was done for which element.

Data mining, visualization: Image parameters





Data mining: Getting the data out...



The measured data is stored in a BCF file. This file contains all the information regarding the measurement.

The data can be extracted or converted in a format that can be read by other software.

Therefore 3 options are available:

- 1) Exporting all single spectra from the map using a script function
- 2) Saving the data block as a RAW file
- 3) Extracting the single element information in the 'element images' of the map window to a TXT file as a number matrix



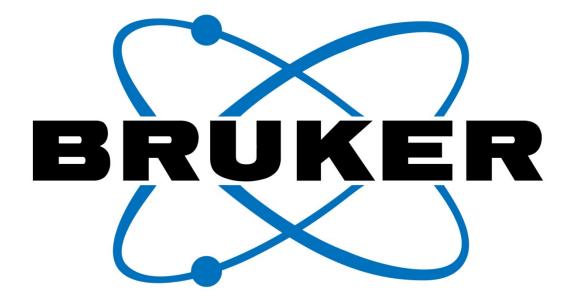


Questions, Thoughts or Comments?

If you have questions or want to contact us during the Webinar, please **type your questions**, thoughts, or comments in the **Q&A box** and **press Submit**.

We ask for your understanding if we do not have time to discuss all comments and questions within the session.

Any unanswered questions or comments will be answered and discussed by email or in another Webex session.



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